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#### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

#### Applications of "[Embedded - Microcontrollers](#)"

##### Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	51
Program Memory Size	384KB (384K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	80K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 22x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f303rdt6">https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f303rdt6</a>

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## 3 Functional overview

### 3.1 ARM® Cortex®-M4 core with FPU with embedded Flash and SRAM

The ARM® Cortex®-M4 processor with FPU is the latest generation of ARM processors for embedded systems. It was developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced response to interrupts.

The ARM® Cortex®-M4 32-bit RISC processor with FPU features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

The processor supports a set of DSP instructions which allows efficient signal processing and complex algorithm execution.

Its single precision FPU speeds up software development by using metalanguage development tools, while avoiding saturation.

With its embedded ARM core, the STM32F303xD/E family is compatible with all ARM tools and software.

*Figure 1* shows the general block diagram of the STM32F303xD/E family devices.

### 3.2 Memory protection unit (MPU)

The memory protection unit (MPU) is used to separate the processing of tasks from the data protection. The MPU manage up to 8 protection areas that are further divided up into 8 subareas. The protection area sizes are between 32 bytes and the whole 4 gigabytes of addressable memory.

The memory protection unit is especially helpful for applications where some critical or certified code has to be protected against the misbehavior of other tasks. It is usually managed by an RTOS (real-time operating system). If a program accesses a memory location that is prohibited by the MPU, the RTOS detects it and takes action. In an RTOS environment, the kernel dynamically updates the MPU area setting, based on the process to be executed.

The MPU is optional and can be bypassed for applications that do not need it.

### 3.3 Embedded Flash memory

All STM32F303xD/E devices feature 384/512 Kbyte of embedded Flash memory available for storing programs and data. The Flash memory access time is adjusted to the CPU clock frequency (0 wait state from 0 to 24 MHz, 1 wait state from 24 to 48 MHz and 2 wait states above).

effective graphic applications using LCD modules with embedded controllers or high performance solutions using external controllers with dedicated acceleration.

## 3.13 Interrupts and events

### 3.13.1 Nested vectored interrupt controller (NVIC)

The STM32F303xD/E devices embed a nested vectored interrupt controller (NVIC) able to handle up to 73 maskable interrupt channels and 16 priority levels.

The NVIC benefits are the following:

- Closely coupled NVIC gives low latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Closely coupled NVIC core interface
- Allows early processing of interrupts
- Processing of late arriving higher priority interrupts
- Support for tail chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

The NVIC hardware block provides flexible interrupt management features with minimal interrupt latency.

## 3.14 Fast analog-to-digital converter (ADC)

Four fast analog-to-digital converters 5 MSPS, with selectable resolution between 12 and 6 bit, are embedded in the STM32F303xD/E family devices. The ADCs have up to 40 external channels. Some of the external channels are shared between ADC1&2 and between ADC3&4. The ADCs can perform conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADCs have also internal channels: Temperature sensor connected to ADC1 channel 16, VBAT/2 connected to ADC1 channel 17, Voltage reference VREFINT connected to the 4 ADCs channel 18, VREFOPAMP1 connected to ADC1 channel 15, VREFOPAMP2 connected to ADC2 channel 17, VREFOPAMP3 connected to ADC3 channel 17 and VREFOPAMP4 connected to ADC4 channel 17.

Additional logic functions embedded in the ADC interface allow:

- Simultaneous sample and hold
- Interleaved sample and hold
- Single-shunt phase current reading techniques.

The ADC can be served by the DMA controller.

Three analog watchdogs are available per ADC.

The analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

communication mode and have LIN Master/Slave capability. The USART interfaces can be served by the DMA controller.

### 3.22 Universal asynchronous receiver transmitter (UART)

The STM32F303xD/E devices have 2 embedded universal asynchronous receiver transmitters (UART4, and UART5). The USART interfaces support IrDA SIR ENDEC, multiprocessor communication mode and single-wire half-duplex communication mode. The USART4 interface can be served by the DMA controller.

Refer to [Table 8](#) for the features available in all U(S)ART interfaces.

**Table 8. USART features**

USART modes/features <sup>(1)</sup>	USART1	USART2	USART3	USART4	USART5
Hardware flow control for modem	X	X	X	-	-
Continuous communication using DMA	X	X	X	X	-
Multiprocessor communication	X	X	X	X	X
Synchronous mode	X	X	X	-	-
Smartcard mode	X	X	X	-	-
Single-wire half-duplex communication	X	X	X	X	X
IrDA SIR ENDEC block	X	X	X	X	X
LIN mode	X	X	X	X	X
Dual clock domain and wakeup from Stop mode	X	X	X	X	X
Receiver timeout interrupt	X	X	X	X	X
Modbus communication	X	X	X	X	X
Auto baud rate detection	X	X	X	-	-
Driver Enable	X	X	X	-	-

1. X = supported.

### 3.23 Serial peripheral interface (SPI)/Inter-integrated sound interfaces (I<sup>2</sup>S)

Up to four SPIs are able to communicate up to 18 Mbit/s in slave and master modes in full-duplex and half-duplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame size is configurable from 4 bits to 16 bits.

Two standard I<sup>2</sup>S interfaces (multiplexed with SPI2 and SPI3) supporting four different audio standards can operate as master or slave at half-duplex and full duplex communication modes. They can be configured to transfer 16 and 24 or 32 bits with 16-bit or 32-bit data resolution and synchronized by a specific signal. Audio sampling frequency from 8 kHz up to 192 kHz can be set by 8-bit programmable linear prescaler. When operating in master mode it can output a clock for an external audio component at 256 times the sampling frequency.

Refer to [Table 9](#) for the features available in SPI1, SPI2, SPI3 and SPI4.

**Table 10. Capacitive sensing GPIOs available on STM32F303xD/E devices (continued)**

Group	Capacitive sensing signal name	Pin name	Group	Capacitive sensing signal name	Pin name
3	TSC_G3_IO1	PC5	7	TSC_G7_IO1	PE2
	TSC_G3_IO2	PB0		TSC_G7_IO2	PE3
	TSC_G3_IO3	PB1		TSC_G7_IO3	PE4
	TSC_G3_IO4	PB2		TSC_G7_IO4	PE5
4	TSC_G4_IO1	PA9	8	TSC_G8_IO1	PD12
	TSC_G4_IO2	PA10		TSC_G8_IO2	PD13
	TSC_G4_IO3	PA13		TSC_G8_IO3	PD14
	TSC_G4_IO4	PA14		TSC_G8_IO4	PD15

**Table 11. Number of capacitive sensing channels available on STM32F303xD/E devices**

Analog I/O group	Number of capacitive sensing channels	
	STM32F303VE/ZE	STM32F303RE
G1	3	3
G2	3	3
G3	3	3
G4	3	3
G5	3	3
G6	3	3
G7	3	0
G8	3	0
Number of capacitive sensing channels	24	18

## 3.28 Development support

### 3.28.1 Serial wire JTAG debug port (SWJ-DP)

The ARM SWJ-DP Interface is embedded, and is a combined JTAG and serial wire debug port that enables either a serial wire debug or a JTAG probe to be connected to the target.

The JTAG TMS and TCK pins are shared respectively with SWDIO and SWCLK and a specific sequence on the TMS pin is used to switch between JTAG-DP and SW-DP.

### 3.28.2 Embedded Trace Macrocell

The ARM embedded trace macrocell (ETM™) provides a greater visibility of the instruction and data flow inside the CPU core by streaming compressed data at a very high rate from the STM32F303xD/E through a small number of ETM™ pins to an external hardware trace

**Figure 7. STM32F303xD/E WLCSP100 ballout**

	1	2	3	4	5	6	7	8	9	10
A	VSS	VSS	PC12	PD2	PB3	PB5	BOOT0	PE1	VDD	VDD
B	VSS	PA15	PD0	PD3	PB4	PB6	PE0	VDD	PE5	VDD
C	PF6	PA14	PD1	PD4	PB7	PB9	VSS	PE4	PC13	PC14 OSC32IN
D	PA12	VDD	PC11	PD7	PB8	PE2	PE3	VBAT	PC15 OSC32OUT	PF9
E	PA10	PA11	PA13	PC10	PA9	PE8	PE6	PF2	NRST	PF10
F	PC8	PC7	PC9	PC6	PA8	PC5	PA2	PE7	PF1 OSCOUT	PF0 OSCIN
G	PD15	PD14	PD13	PD9	PE12	PC4	PA3	PC2	PC1	PC0
H	PD12	PD11	PD10	PB15	PE11	PA6	PA5	VSSA	PA0	PC3
J	VSS	PB14	PB13	PB12	VDD	PB0	PA4	VREF+	PA1	VDDA
K	VSS	VSS	PB11	PB10	PB2	PB1	PA7	VDD	VSS	VSS

MSv40453V1

**Table 12. Legend/abbreviations used in the pinout table**

Name	Abbreviation	Definition
Pin name	Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
I/O structure	FT	5 V tolerant I/O
	FTf	5 V tolerant I/O, I <sup>2</sup> C FM+ option
	TTa	3.3 V tolerant I/O
	TC	Standard 3.3V I/O
	B	Dedicated to BOOT0 pin
	RST	Bi-directional reset pin with embedded weak pull-up resistor
Notes	Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset	
Pin functions	Alternate functions	Functions selected through GPIOx_AFR registers
	Additional functions	Functions directly selected/enabled through peripheral registers

Table 13. STM32F303xD/E pin definitions (continued)

Pin number					Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
LQFP64	LQFP100	UFBGA100	WL CSP100	LQFP144						
-	45	M11	-	67	PE14	I/O	TTa	<sup>(1)</sup>	EVENTOUT, TIM1_CH4, SPI4_MOSI, TIM1_BKIN2, FMC_D11	ADC4_IN1 <sup>(3)</sup>
-	46	M12	-	68	PE15	I/O	TTa	<sup>(1)</sup>	EVENTOUT, TIM1_BKIN, USART3_RX, FMC_D12	ADC4_IN2 <sup>(3)</sup>
29	47	L10	K4	69	PB10	I/O	TTa	-	TIM2_CH3, TSC_SYNC, USART3_TX, EVENTOUT	COMP5_INM, OPAMP3_VINM, OPAMP4_VINM
30	48	L11	K3	70	PB11	I/O	TTa	-	TIM2_CH4, TSC_G6_IO1, USART3_RX, EVENTOUT	ADC12_IN14, COMP6_INP, OPAMP4_VINP
31	49	F12	K1, J1, K2	71	VSS	S	-	-	-	-
32	50	G12	J5	72	VDD	S	-	-	-	-
33	51	L12	J4	73	PB12	I/O	TTa	<sup>(5)</sup>	TSC_G6_IO2, I2C2_SMBAL, SPI2 NSS/I2S2_WS, TIM1_BKIN, USART3_CK, EVENTOUT	ADC4_IN3 <sup>(3)</sup> , COMP3_INM, OPAMP4_VOUT
34	52	K12	J3	74	PB13	I/O	TTa	-	TSC_G6_IO3, SPI2_SCK/I2S2_CK, TIM1_CH1N, USART3_CTS, EVENTOUT	ADC3_IN5 <sup>(3)</sup> , COMP5_INP, OPAMP3_VINP, OPAMP4_VINP
35	53	K11	J2	75	PB14	I/O	TTa	-	TIM15_CH1, TSC_G6_IO4, SPI2_MISO/I2S2ext_SD, TIM1_CH2N, USART3_RTS, EVENTOUT	ADC4_IN4 <sup>(3)</sup> , COMP3_INP, OPAMP2_VINP
36	54	K10	H4	76	PB15	I/O	TTa	-	RTC_REFIN, TIM15_CH2, TIM15_CH1N, TIM1_CH3N, SPI2_MOSI/I2S2_SD, EVENTOUT	ADC4_IN5 <sup>(3)</sup> , COMP6_INM
-	55	K9	-	77	PD8	I/O	TTa	<sup>(1)</sup>	EVENTOUT, USART3_TX, FMC_D13	ADC4_IN12, OPAMP4_VINM

Table 13. STM32F303xD/E pin definitions (continued)

Pin number						Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
LQFP64	LQFP100	UFBGA100	WL CSP100	LQFP144							
37	63	E12	F4	96	PC6	I/O	FT	-		EVENTOUT, TIM3_CH1, TIM8_CH1, I2S2_MCK, COMP6_OUT	-
38	64	E11	F2	97	PC7	I/O	FT	-		EVENTOUT, TIM3_CH2, TIM8_CH2, I2S3_MCK, COMP5_OUT	-
39	65	E10	F1	98	PC8	I/O	FT	-		EVENTOUT, TIM3_CH3, TIM8_CH3, COMP3_OUT	-
40	66	D12	F3	99	PC9	I/O	FTf	-		EVENTOUT, TIM3_CH4, I2C3_SDA, TIM8_CH4, I2SCKIN, TIM8_BKIN2	-
41	67	D11	F5	100	PA8	I/O	FTf	-		MCO, I2C3_SCL, I2C2_SMBAL, I2S2_MCK, TIM1_CH1, USART1_CK, COMP3_OUT, TIM4_ETR, EVENTOUT	-
42	68	D10	E5	101	PA9	I/O	FTf	-		I2C3_SMBAL, TSC_G4_IO1, I2C2_SCL, I2S3_MCK, TIM1_CH2, USART1_TX, COMP5_OUT, TIM15_BKIN, TIM2_CH3, EVENTOUT	-
43	69	C12	E1	102	PA10	I/O	FTf	-		TIM17_BKIN, TSC_G4_IO2, I2C2_SDA, SPI2_MISO/I2S2ext_SD, TIM1_CH3, USART1_RX, COMP6_OUT, TIM2_CH4, TIM8_BKIN, EVENTOUT	-
44	70	B12	E2	103	PA11	I/O	FT	-		SPI2_MOSI/I2S2_SD, TIM1_CH1N, USART1_CTS, COMP1_OUT, CAN_RX, TIM4_CH1, TIM1_CH4, TIM1_BKIN2, EVENTOUT	USB_DM

Table 14. STM32F303xD/E alternate function mapping (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		SYS_AF	TIM2/15/16/17/EVENT	I2C3/TIM1/2/3/4/8/20/15/GPCOMP1/MP1	I2C3/TIM8/20/15/GPCOMP7/TSC	I2C1/2/TIM1/8/16/17	SPI1/SPI2/I2S2/SPI3/I2S3/SPI4/UART4/5/TIM8/Infra red	SPI2/I2S2/SPI3/I2S3/TIM1/8/20/Infrared	USART1/2/3/CAN/GP COMP3/5/6	I2C3/GPCOMP1/2/3/4/5/6	CAN/TIM1/8/15	TIM2/3/4/8/17	TIM1/8	FSMC/TIM1	-	-	EVENT
B <sub>10</sub> P	PB4	JTRST	TIM16_CH1	TIM3_CH1	TSC_G5_!O2	TIM8_CH2N	SPI1_MISO	SPI3_MISO/I2S3ext_SD	USART2_RX	-	-	TIM17_BKIN	-	-	-	-	EVENT OUT
	PB5	-	TIM16_BKIN	TIM3_CH2	TIM8_CH3N	I2C1_SMBAI	SPI1_MOSI	SPI3_MO SI/I2S3_SD	USART2_CK	I2C3_SDA	-	TIM17_CH1	-	-	-	-	EVENT OUT
	PB6	-	TIM16_CH1N	TIM4_CH1	TSC_G5_!O3	I2C1_SCL	TIM8_CH1	TIM8_ETR	USART1_TX	-	-	TIM8_BKIN2	-	-	-	-	EVENT OUT
	PB7	-	TIM17_CH1N	TIM4_CH2	TSC_G5_!O4	I2C1_SDA	TIM8_BKIN	-	USART1_RX	-	-	TIM3_CH4	-	FMC_NADV	-	-	EVENT OUT
	PB8	-	TIM16_CH1	TIM4_CH3	TSC_SYNC	I2C1_SCL	-	-	USART3_RX	COMP1_OUT	CAN_RX	TIM8_CH2	-	TIM1_BKIN	-	-	EVENT OUT
	PB9	-	TIM17_CH1	TIM4_CH4	-	I2C1_SDA	-	IR-OUT	USART3_TX	COMP2_OUT	CAN_TX	TIM8_CH3	-	-	-	-	EVENT OUT
	PB10	-	TIM2_CH3	-	TSC_SYNC	-	-	-	USART3_TX	-	-	-	-	-	-	-	EVENT OUT
	PB11	-	TIM2_CH4	-	TSC_G6_!O1	-	-	-	USART3_RX	-	-	-	-	-	-	-	EVENT OUT
	PB12	-	-	-	TSC_G6_!O2	I2C2_SMBAL	SPI2 NSS/I2S2_WS	TIM1_BKIN	USART3_CK	-	-	-	-	-	-	-	EVENT OUT
	PB13	-	-	-	TSC_G6_!O3	-	SPI2_SCK/I2S2_CK	TIM1_CH1N	USART3_CTS	-	-	-	-	-	-	-	EVENT OUT



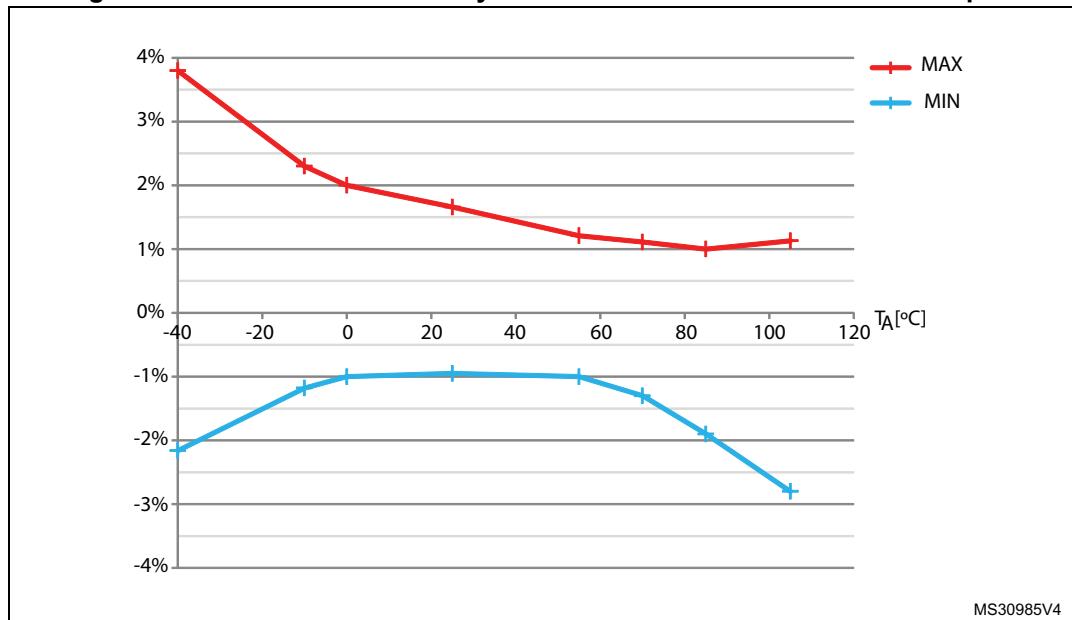
**Table 15. Memory map, peripheral register boundary addresses**

<b>Bus</b>	<b>Boundary address</b>	<b>Size (bytes)</b>	<b>Peripheral</b>
AHB4	0xA000 0000 - 0xA000 0FFF	4 K	FSMC control registers
	0x8000 0000 - 0x9FFF FFFF	512 M	FSMC Banks 3 and 4
	0x6000 0000 - 0x7FFF FFFF	512 M	FSMC Banks 1 and 2
-	0x5000 0800 - 0x5FFF FFFF	384 M	Reserved
AHB3	0x5000 0400 - 0x5000 07FF	1 K	ADC3 - ADC4
	0x5000 0000 - 0x5000 03FF	1 K	ADC1 - ADC2
-	0x4800 2000 - 0x4FFF FFFF	~132 M	Reserved
AHB2	0x4800 1C00 - 0x4800 1FFF	1 K	GPIOH
	0x4800 1800 - 0x4800 1BFF	1 K	GPIOG
	0x4800 1400 - 0x4800 17FF	1 K	GPIOF
	0x4800 1000 - 0x4800 13FF	1 K	GPIOE
	0x4800 0C00 - 0x4800 0FFF	1 K	GPIOD
	0x4800 0800 - 0x4800 0BFF	1 K	GPIOC
	0x4800 0400 - 0x4800 07FF	1 K	GPIOB
	0x4800 0000 - 0x4800 03FF	1 K	GPIOA
-	0x4002 4400 - 0x47FF FFFF	~128 M	Reserved
AHB1	0x4002 4000 - 0x4002 43FF	1 K	TSC
	0x4002 3400 - 0x4002 3FFF	3 K	Reserved
	0x4002 3000 - 0x4002 33FF	1 K	CRC
	0x4002 2400 - 0x4002 2FFF	3 K	Reserved
	0x4002 2000 - 0x4002 23FF	1 K	Flash interface
	0x4002 1400 - 0x4002 1FFF	3 K	Reserved
	0x4002 1000 - 0x4002 13FF	1 K	RCC
	0x4002 0800 - 0x4002 0FFF	2 K	Reserved
	0x4002 0400 - 0x4002 07FF	1 K	DMA2
	0x4002 0000 - 0x4002 03FF	1 K	DMA1

Table 32. Switching output I/O current consumption

Symbol	Parameter	Conditions <sup>(1)</sup>	I/O toggling frequency (f <sub>SW</sub> )	Typ	Unit
I <sub>SW</sub>	I/O current consumption	$V_{DD} = 3.3 \text{ V}$ $C_{ext} = 0 \text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	0.90	mA
			4 MHz	0.93	
			8 MHz	1.16	
			18 MHz	1.60	
			36 MHz	2.51	
			48 MHz	2.97	
		$V_{DD} = 3.3 \text{ V}$ $C_{ext} = 10 \text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	0.93	
			4 MHz	1.06	
			8 MHz	1.47	
			18 MHz	2.26	
			36 MHz	3.39	
			48 MHz	5.99	
		$V_{DD} = 3.3 \text{ V}$ $C_{ext} = 22 \text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	1.03	
			4 MHz	1.30	
			8 MHz	1.79	
			18 MHz	3.01	
			36 MHz	5.99	
		$V_{DD} = 3.3 \text{ V}$ $C_{ext} = 33 \text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	1.10	
			4 MHz	1.31	
			8 MHz	2.06	
			18 MHz	3.47	
			36 MHz	8.35	
		$V_{DD} = 3.3 \text{ V}$ $C_{ext} = 47 \text{ pF}$ $C = C_{INT} + C_{EXT} + C_S$	2 MHz	1.20	
			4 MHz	1.54	
			8 MHz	2.46	
			18 MHz	4.51	
			36 MHz	9.98	

1. CS = 5 pF (estimated value).

**Figure 19. HSI oscillator accuracy characterization results for soldered parts****Low-speed internal (LSI) RC oscillator****Table 41. LSI oscillator characteristics<sup>(1)</sup>**

Symbol	Parameter	Min	Typ	Max	Unit
f <sub>LSI</sub>	Frequency	30	40	50	kHz
t <sub>su(LSI)</sub> <sup>(2)</sup>	LSI oscillator startup time	-	-	85	μs
I <sub>DD(LSI)</sub> <sup>(2)</sup>	LSI oscillator power consumption	-	0.75	1.2	μA

1. V<sub>DDA</sub> = 3.3 V, T<sub>A</sub> = -40 to 105 °C unless otherwise specified.

2. Guaranteed by design, not tested in production.

**6.3.9 PLL characteristics**

The parameters given in [Table 42](#) are derived from tests performed under ambient temperature and supply voltage conditions summarized in [Table 19](#).

**Table 42. PLL characteristics**

Symbol	Parameter	Value			Unit
		Min	Typ	Max	
f <sub>PLL_IN</sub>	PLL input clock <sup>(1)</sup>	1 <sup>(2)</sup>	-	24 <sup>(2)</sup>	MHz
	PLL input clock duty cycle	40 <sup>(2)</sup>	-	60 <sup>(2)</sup>	%
f <sub>PLL_OUT</sub>	PLL multiplier output clock	16 <sup>(2)</sup>	-	72	MHz
t <sub>LOCK</sub>	PLL lock time	-	-	200 <sup>(2)</sup>	μs
Jitter	Cycle-to-cycle jitter	-	-	300 <sup>(2)</sup>	ps

1. Take care of using the appropriate multiplier factors so as to have PLL input clock values compatible with the range defined by f<sub>PLL\_OUT</sub>.

2. Guaranteed by design, not tested in production.

**Table 56. Synchronous non-multiplexed PSRAM write timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(CLK)}$	FMC_CLK period	2THCLK-1	-	ns
$t_{d(CLKL-NExL)}$	FMC_CLK low to FMC_NEx low (x=0..2)	-	6	
$t_{d(CLKH-NExH)}$	FMC_CLK high to FMC_NEx high (x= 0...2)	THCLK+1.5	-	
$t_{d(CLKL-NADVl)}$	FMC_CLK low to FMC_NADV low	-	7.5	
$t_{d(CLKL-NADVh)}$	FMC_CLK low to FMC_NADV high	0	-	
$t_{d(CLKL-AV)}$	FMC_CLK low to FMC_Ax valid (x=16...25)	-	6.5	
$t_{d(CLKH-AIV)}$	FMC_CLK high to FMC_Ax invalid (x=16...25)	0	-	
$t_{d(CLKL-NWEL)}$	FMC_CLK low to FMC_NWE low	-	0	
$t_{d(CLKH-NWEH)}$	FMC_CLK high to FMC_NWE high	THCLK+2	-	
$t_{d(CLKL-Data)}$	FMC_D[15:0] valid data after FMC_CLK low	-	7.5	
$t_{d(CLKL-NBLL)}$	FMC_CLK low to FMC_NBL low	-	7	
$t_{d(CLKH-NBLH)}$	FMC_CLK high to FMC_NBL high	THCLK+0.5	-	
$t_{su(NWAIT-CLKH)}$	FMC_NWAIT valid before FMC_CLK high	2	-	
$t_{h(CLKH-NWAIT)}$	FMC_NWAIT valid after FMC_CLK high	4	-	

1. Based on characterization, not tested in production.

### PC Card/CompactFlash controller waveforms and timings

*Figure 28* to *Figure 33* present the PC Card/Compact Flash controller waveforms, and *Table 57* to *Table 58* provide the corresponding timings. The results shown in this table are obtained with the following FSMC configuration:

- COM.FMC\_SetupTime = 0x04;
- COM.FMC\_WaitSetupTime = 0x07;
- COM.FMC\_HoldSetupTime = 0x04;
- COM.FMC\_HiZSetupTime = 0x05;
- ATT.FMC\_SetupTime = 0x04;
- ATT.FMC\_WaitSetupTime = 0x07;
- ATT.FMC\_HoldSetupTime = 0x04;
- ATT.FMC\_HiZSetupTime = 0x05;
- IO.FMC\_SetupTime = 0x04;
- IO.FMC\_WaitSetupTime = 0x07;
- IO.FMC\_HoldSetupTime = 0x04;
- IO.FMC\_HiZSetupTime = 0x05;
- TCLRSetupTime = 0;
- TARSetupTime = 0.

In all timing tables, the THCLK is the HCLK clock period.

**Table 78. USB: full-speed electrical characteristics<sup>(1)</sup> (continued)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{rfm}$	Rise/ fall time matching	$t_r/t_f$	90	-	110	%
$V_{CRS}$	Output signal crossover voltage	-	1.3	-	2.0	V
Output driver Impedance <sup>(3)</sup>	$Z_{DRV}$	driving high and low	28	40	44	$\Omega$

1. Guaranteed by design, not tested in production.
2. Measured from 10% to 90% of the data signal. For more detailed information, refer to USB Specification - Chapter 7 (version 2.0).
3. No external termination series resistors are required on USB\_DP (D+) and USB\_DM (D-), the matching impedance is already included in the embedded driver.

### CAN (controller area network) interface

Refer to [Section 6.3.15: I/O port characteristics](#) for more details on the input/output alternate function characteristics (CAN\_TX and CAN\_RX).

### 6.3.19 ADC characteristics

Unless otherwise specified, the parameters given in [Table 79](#) to [Table 82](#) are guaranteed by design, with conditions summarized in [Table 19](#).

**Table 79. ADC characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{DDA}$	Analog supply voltage for ADC	-	2.0	-	3.6	V
$I_{DDA}$	Current on VDDA pin (see <a href="#">Figure 48</a> )	Single-ended mode, 5 MSPS	-	907	1033	$\mu A$
		Single-ended mode, 1 MSPS	-	194	285.5	
		Single-ended mode, 200 KSPS	-	51.5	70	
		Differential mode, 5 MSPS	-	887.5	1009	
		Differential mode, 1 MSPS	-	212	285	
		Differential mode, 200 KSPS	-	51	69.5	

Table 81. ADC accuracy - limited test conditions, 100-/144-pin packages <sup>(1)(2)</sup> (continued)

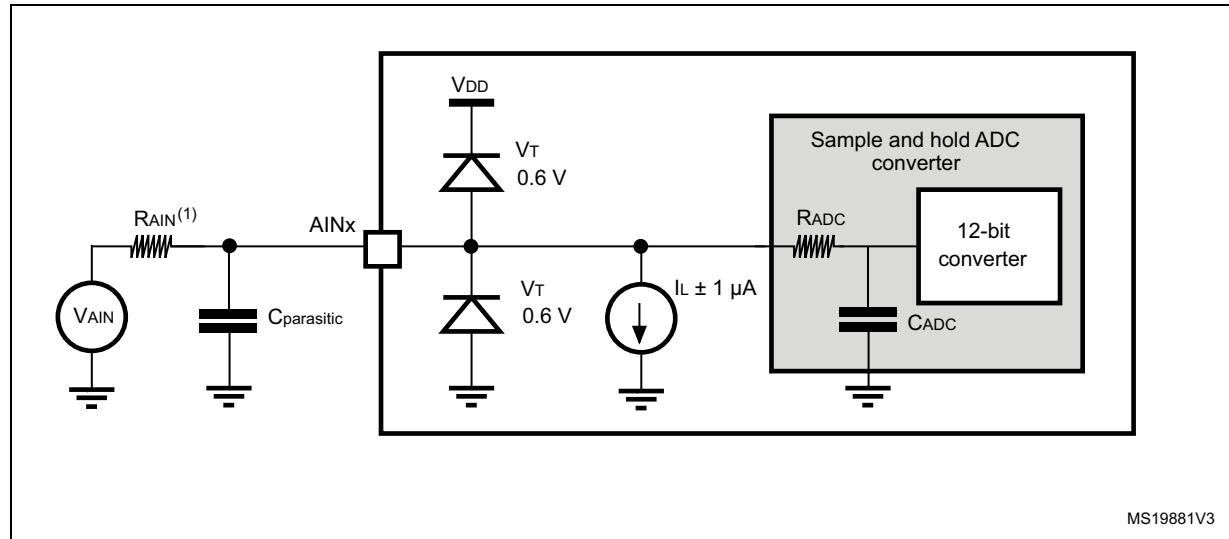
Symbol	Parameter	Conditions				Min (3)	Typ	Max (3)	Unit
SNR <sup>(4)</sup>	Signal-to-noise ratio	ADC clock freq. $\leq$ 72 MHz Sampling freq $\leq$ 5 Msps $V_{DDA} = V_{REF+} = 3.3$ V 25°C 100-pin/144-pin package	Single ended	Fast channel 5.1 Ms	66	67	-	dB	
				Slow channel 4.8 Ms	66	67	-		
			Differential	Fast channel 5.1 Ms	69	70	-		
				Slow channel 4.8 Ms	69	70	-		
	Total harmonic distortion		Single ended	Fast channel 5.1 Ms	-	-76	-76		
				Slow channel 4.8 Ms	-	-76	-76		
			Differential	Fast channel 5.1 Ms	-	-80	-80		
				Slow channel 4.8 Ms	-	-80	-80		

1. ADC DC accuracy values are measured after internal calibration.
2. ADC accuracy vs. negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.  
Any positive injection current within the limits specified for  $I_{INJ(PIN)}$  and  $\Sigma I_{INJ(PIN)}$  in [Section 6.3.15](#) does not affect the ADC accuracy.
3. Data based on characterization results, not tested in production.
4. Value measured with a -0.5 dB full scale 50 kHz sine wave input signal.

Table 82. ADC accuracy, 100-pin/144-pin packages <sup>(1)(2)(3)</sup>

Symbol	Parameter	Conditions				Min (4)	Max <sup>(4)</sup>	Unit
ET	Total unadjusted error	ADC clock freq. $\leq$ 72 MHz, Sampling freq. $\leq$ 5 Msps $2.0 \text{ V} \leq V_{DDA}, V_{REF+} \leq 3.6 \text{ V}$ 100-pin/144-pin package	Single Ended	Fast channel 5.1 Ms	-	$\pm 6.5$	LSB	
				Slow channel 4.8 Ms	-	$\pm 6.5$		
			Differential	Fast channel 5.1 Ms	-	$\pm 4$		
				Slow channel 4.8 Ms	-	$\pm 4$		
	EO		Single Ended	Fast channel 5.1 Ms	-	$\pm 3$		
				Slow channel 4.8 Ms	-	$\pm 3$		
			Differential	Fast channel 5.1 Ms	-	$\pm 2$		
				Slow channel 4.8 Ms	-	$\pm 2$		
EG	Gain error		Single Ended	Fast channel 5.1 Ms	-	$\pm 6$		
				Slow channel 4.8 Ms	-	$\pm 6$		
			Differential	Fast channel 5.1 Ms	-	$\pm 3$		
				Slow channel 4.8 Ms	-	$\pm 3$		
	ED		Single Ended	Fast channel 5.1 Ms	-	$\pm 1.5$		
				Slow channel 4.8 Ms	-	$\pm 1.5$		
			Differential	Fast channel 5.1 Ms	-	$\pm 1.5$		
				Slow channel 4.8 Ms	-	$\pm 1.5$		

Figure 51. Typical connection diagram using the ADC



1. Refer to [Table 79](#) for the values of  $R_{AIN}$ .
2.  $C_{parasitic}$  represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high  $C_{parasitic}$  value downgrades conversion accuracy. To remedy this,  $f_{ADC}$  should be reduced.

### General PCB design guidelines

Power supply decoupling should be performed as shown in [Figure 12](#). The 10 nF capacitor should be ceramic (good quality) and it should be placed as close as possible to the chip.

### 6.3.20 DAC electrical specifications

Table 86. DAC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{DDA}$	Analog supply voltage	-	2.4	-	3.6	V
$R_{LOAD}^{(1)}$	Resistive load	DAC output buffer ON	5	-	-	kΩ
$R_L$	Resistive load	Dac output buffer ON: connected to $V_{SSA}$	5	-	-	kΩ
		Dac output buffer ON: connected to $V_{DDA}$	25	-	-	kΩ
$R_O^{(1)}$	Output impedance	DAC output buffer OFF	-	-	15	kΩ
$C_{LOAD}^{(1)}$	Capacitive load	DAC output buffer ON	-	-	50	pF
$V_{DAC\_OUT}^{(1)}$	Voltage on DAC_OUT output	Corresponds to 12-bit input code (0x0E0) to (0xF1C) at $V_{DDA} = 3.6$ V and (0x155) and (0xEAB) at $V_{DDA} = 2.4$ V DAC output buffer ON.	0.2	-	$V_{DDA} - 0.2$	V
		DAC output buffer OFF	-	0.5	$V_{DDA} - 1LSB$	mV

**Table 92. LQFP144 mechanical data**

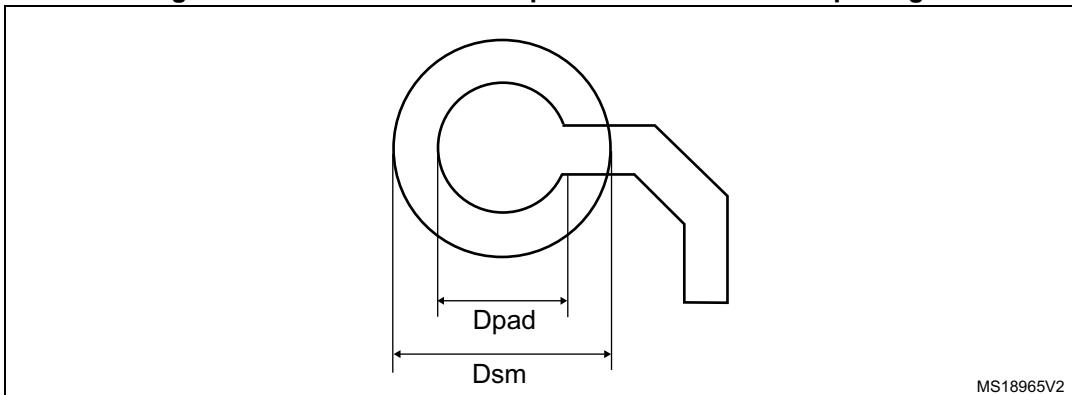
<b>Symbol</b>	<b>millimeters</b>			<b>inches<sup>(1)</sup></b>		
	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	21.800	22.000	22.200	0.8583	0.8661	0.8740
D1	19.800	20.000	20.200	0.7795	0.7874	0.7953
D3	-	17.500	-	-	0.6890	-
E	21.800	22.000	22.200	0.8583	0.8661	0.8740
E1	19.800	20.000	20.200	0.7795	0.7874	0.7953
E3	-	17.500	-	-	0.6890	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Table 93. UFBGA100 package mechanical data (continued)**

<b>Symbol</b>	<b>millimeters</b>			<b>inches<sup>(1)</sup></b>		
	<b>Min.</b>	<b>Typ.</b>	<b>Max.</b>	<b>Min.</b>	<b>Typ.</b>	<b>Max.</b>
ddd	-	-	0.100	-	-	0.0039
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 58. Recommended footprint for the UFBGA100 package****Table 94. UFBGA100 recommended PCB design rules (0.5 mm pitch BGA)**

<b>Dimension</b>	<b>Recommended values</b>
Pitch	0.5
Dpad	0.27 mm
Dsm	0.35 mm typ. (depends on the soldermask registration tolerance)
Solder paste	0.27 mm aperture diameter.

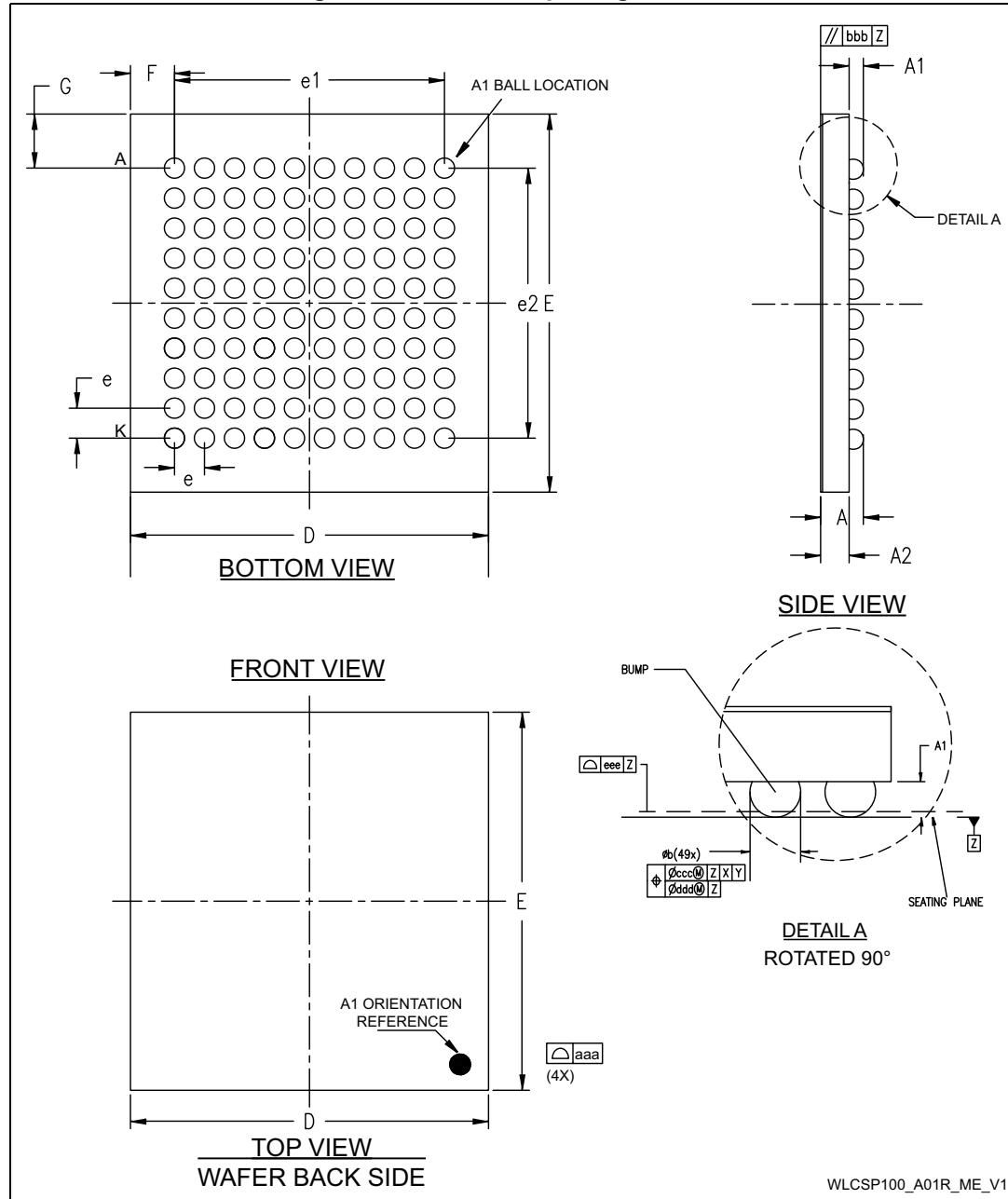
**Note:** Non-solder mask defined (NSMD) pads are recommended.

**Note:** 4 to 6 mils solder paste screen printing process.

## 7.5 WLCSP100 package information

WLCSP100 is a 100-ball, 4.775 x 5.041 mm, 0.4 mm pitch wafer level chip scale package.

**Figure 63.WLCSP100 package outline**



1. Drawing is not to scale.